TOSHIBA GTR Module Silicon N Channel IGBT

MG100J7KS50

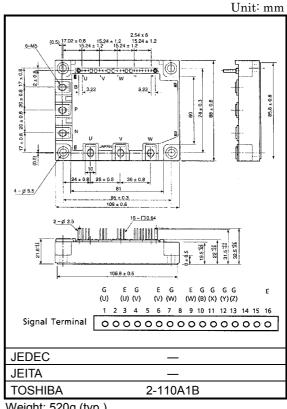
High Power Switching Applications Motor Control Applications

- The electrodes are isolated from case.
- High input impedance
- 7 IGBTs built into 1 package.
- Enhancement-mode
- High speed type IGBT

 $: V_{CE (sat)} = 2.5 \text{ V (max) (@I_{C} = 100 \text{ A})}$

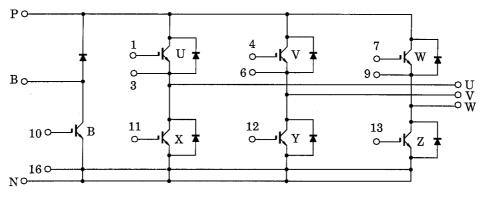
 $: t_f = 0.5 \mu s \text{ (max) (@IC = 100 A)}$

 $t_{rr} = 0.3 \ \mu s \ (max) \ (@I_F = 100 \ A)$



Weight: 520g (typ.)

Equivalent Circuit



Signal Terminal

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1	: G (U)	2 : Open	3 : E (U)	4 : G (V)
5	: Open	$6 : \mathbf{E}(\mathbf{V})$	7 : G (W)	8 : Open
9	: E (W)	10:G(B)	11: G(X)	12:G(Y)
13	: G (Z)	14 : Open	15 : Open	16 : E

2001-08-16

Inverter Stage

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-emitter voltage	V _{CES}	600	V		
Gate-emitter voltage	V _{GES}	±20	V		
Collector current	DC	I _C	100	Α	
Collector current	1ms	I _{CP}	200	A	
Forward current	DC	IF	100	Α	
i oiwaid cuiteiit	1ms	I _{FM}	200	^	
Collector power dissipation (To	PC	300	W		
Junction temperature	Tj	150	°C		
Storage temperature range	T _{stg}	− 40 ~ 125	°C		
Isolation voltage	V _{Isol}	2500 (AC 1min.)	V		
Screw torque (Terminal / mour	_	3/3	N·m		

Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GES}	V _{GE} = ±20V, V _{CE} = 0V	_	_	±500	nA
Collector cut-off current		I _{CES}	V _{CE} = 600V, V _{GE} = 0V	-	_	1.0	mA
Gate-emitter cut-off voltage		V _{GE (off)}	V _{CE} = 5 V, I _C = 10 mA	5.0	_	8.0	V
Collector-emitter saturation voltage		V _{CE} (sat)	I _C = 100 A, V _{GE} = 15 V	-	2.0	2.5	V
Input capacitance		C _{ies}	V _{CE} = 10 V, V _{GE} = 0 V, f = 1 MHz	-	8.5	_	nF
Forward voltage		V _F	I _F = 100 A	-	2.3	3.0	V
	Rise time	t _r	Inductive load $V_{CC} = 300 \text{ V}$ $I_C = 100 \text{ A}$ $V_{GE} = \pm 15 \text{ V}$ $R_G = 13 \Omega$ (Note 1)	_	0.12	0.24	μѕ
	Turn-on time	t _{on}		_	0.45	0.90	
Switching time	Fall time	t _f		_	0.20	0.50	
	Turn-off time	t _{off}		_	0.50	1.00	
	Reverse recovery time	trr		_	0.10	0.30	
Thermal resistance		R _{th (j-c)}	Transistor stage	_	_	0.42	
		R _{th (c-f)}	Diode stage	_	_	1.00	°C/W
			Case to fin (Note 2)		0.05	_	

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Note 2: Silicone grease is applied.

Brake Stage

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Collector-emitter voltage	V _{CES}	600	V	
Gate-emitter voltage	V _{GES}	±20	V	
Reverse voltage	V _R	600	V	
Collector current	DC	IC	50	Α
Collector current	1ms	I _{CP}	100	A
Forward current	DC	l _F	50	Α
Forward current	1ms	I _{FM}	100	A
Collector power dissipation (PC	80	W	
Junction temperature	Tj	150	°C	
Storage temperature range	T _{stg}	- 40 ~ 125	°C	
Isolation voltage	V _{Isol}	2500 (AC 1 min.)	V	
Screw torque (Terminal / mo	_	3/3	N·m	

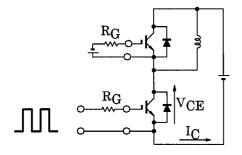
Electrical Characteristics (Ta = 25°C)

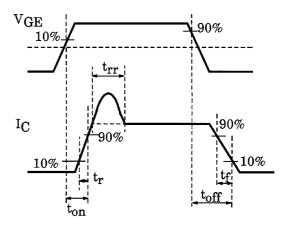
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GES}	V _{GE} = ±20 V, V _{CE} = 0 V	_	_	±500	nA
Collector cut-off current		I _{CES}	V _{CE} = 600 V, V _{GE} = 0 V	-	_	1.0	mA
Gate-emitter cut-off voltage		V _{GE} (off)	V _{CE} = 5 V, I _C = 5 mA	5.0	_	8.0	V
Collector-emitter saturation voltage		V _{CE (sat)}	I _C = 50 A, V _{GE} = 15 V	_	2.0	2.5	V
Input capacitance		C _{ies}	V _{CE} = 10 V, V _{GE} = 0 V, f = 1 MHz	_	4.0	_	nF
Reverse current		I _R	V _R = 600 V	_	_	1.0	mA
Forward voltage		V _F	I _F = 50 A	_	2.2	2.8	V
	Rise time	t _r	Inductive-load $V_{CC} = 300 \text{ V}$ $I_C = 50 \text{ A}$ $V_{GE} = \pm 15 \text{ V}$ $R_G = 24 \Omega$ (Note 1)	_	0.08	0.16	μs
	Turn-on time	t _{on}		_	0.10	0.20	
Switching time	Fall time	t _f			0.22	0.44	
	Turn-off time	t _{off}			0.50	1.00	
	Reverserecovery time	trr		_	0.23	0.35	
Thermal resistance		R _{th (j-c)}	Transistor stage	_	_	1.56	
		R _{th (c-f)}	Diode stage	_	_	2.00	°C/W
			Case to fin (Note 2)	_	0.05	_	

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Note 2: Silicone grease is applied.

Note 1: Switching time test circuit & timing chart





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